

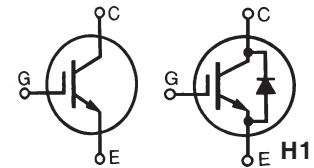
# High Voltage IGBT

**IXGH 16N170A**  
**IXGT 16N170A**  
**IXGH 16N170AH1**  
**IXGT 16N170AH1**

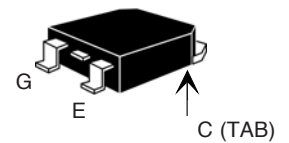
**V<sub>CES</sub> = 1700 V**  
**I<sub>C25</sub> = 16 A**  
**V<sub>CE(sat)</sub> = 5.0 V**  
**t<sub>fi(typ)</sub> = 70 ns**

## Preliminary Data Sheet

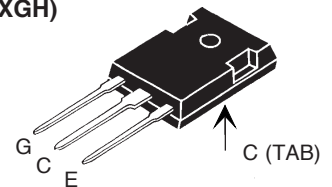
Symbol	Test Conditions	Maximum Ratings
V <sub>CES</sub>	T <sub>J</sub> = 25°C to 150°C	1700 V
V <sub>CGR</sub>	T <sub>J</sub> = 25°C to 150°C; R <sub>GE</sub> = 1 MΩ	1700 V
V <sub>GES</sub>	Continuous	±20 V
V <sub>GEM</sub>	Transient	±30 V
I <sub>C25</sub>	T <sub>C</sub> = 25°C	16 A
I <sub>C90</sub>	T <sub>C</sub> = 90°C	11 A
I <sub>F90</sub>	T <sub>C</sub> = 90°C, Diode	17 A
I <sub>CM</sub>	T <sub>C</sub> = 25°C, 1 ms	40 A
<b>SSOA (RBSOA)</b>	V <sub>GE</sub> = 15 V, T <sub>VJ</sub> = 125°C, R <sub>G</sub> = 10Ω Clamped inductive load	I <sub>CM</sub> = 40 @ 0.8 V <sub>CES</sub>
t <sub>SC</sub>	T <sub>J</sub> = 125°C, V <sub>CE</sub> = 1200 V; V <sub>GE</sub> = 15 V, R <sub>G</sub> = 22Ω	10 μs
P <sub>C</sub>	T <sub>C</sub> = 25°C	190 W
T <sub>J</sub>		-55 ... +150 °C
T <sub>JM</sub>		150 °C
T <sub>stg</sub>		-55 ... +150 °C
M <sub>d</sub>	Mounting torque (M3)	TO-247 1.13/10Nm/lb.in.
	Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s	300 °C
	Plastic body for 10s	260 °C
<b>Weight</b>		TO-247 6 g TO-268 4 g



**TO-268 (IXGT)**



**TO-247 (IXGH)**



G = Gate  
E = Emitter  
C = Collector,  
TAB = Collector

### Features

- High blocking voltage
- High current handling capability
- MOS Gate turn-on - drive simplicity
- Rugged NPT structure
- Molding epoxies meet UL 94 V-0 flammability classification
- SONIC-FRD™ fast recovery copack diode
- International standard packages JEDEC TO-268 and JEDEC TO-247 AD

### Applications

- Capacitor discharge & pulser circuits
- AC motor speed control
- DC servo and robot drives
- DC choppers
- Uninterruptible power supplies (UPS)
- Switched-mode and resonant-mode power supplies

### Advantages

- High power density
- Suitable for surface mounting
- Easy to mount with 1 screw, (isolated mounting screw hole)

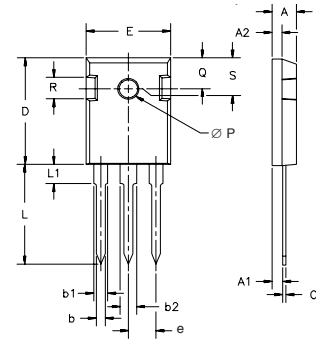
Symbol	Test Conditions	Characteristic Values (T <sub>J</sub> = 25°C, unless otherwise specified)		
		min.	typ.	max.
BV <sub>CES</sub>	I <sub>C</sub> = 250 μA, V <sub>GE</sub> = 0 V	1700		V
V <sub>GE(th)</sub>	I <sub>C</sub> = 250 μA, V <sub>CE</sub> = V <sub>GE</sub>	3.0		V
I <sub>CES</sub>	V <sub>CE</sub> = 0.8 · V <sub>CES</sub> V <sub>GE</sub> = 0 V, Note 1 T <sub>J</sub> = 125°C	16N170A		50 μA
		16N170AH1		100 μA
		16N170A		750 μA
		16N170AH1		1.5 mA
I <sub>GES</sub>	V <sub>CE</sub> = 0 V, V <sub>GE</sub> = ±20 V			±100 nA
V <sub>CE(sat)</sub>	I <sub>C</sub> = I <sub>C90</sub> , V <sub>GE</sub> = 15 V T <sub>J</sub> = 125°C		4.0	V
			4.8	V

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ unless otherwise specified)		
		min.	typ.	max.
$g_{fs}$	$I_C = I_{C25}; V_{CE} = 10\text{ V}$ Note 2	7	13	S
$C_{ies}$	$V_{CE} = 25\text{ V}, V_{GE} = 0\text{ V}, f = 1\text{ MHz}$	16N170A 16N170AH1	1620	pF
$C_{oes}$			83	pF
$C_{res}$			31	pF
$Q_g$	$I_C = I_{C90}; V_{GE} = 15\text{ V}, V_{CE} = 0.5 V_{CES}$	16N170A 16N170AH1	83	nC
$Q_{ge}$			10	nC
$Q_{gc}$			31	nC
$t_{d(on)}$	<b>Inductive load, <math>T_J = 25^\circ\text{C}</math></b>	16N170A 16N170AH1	36	ns
$t_{ri}$	$I_C = I_{C25}, V_{GE} = 15\text{ V}, R_G = 10\ \Omega$		57	ns
$t_{d(off)}$	$V_{CE} = 0.5 V_{CES}$ , Note 3		160	300 ns
$t_{fi}$			70	150 ns
$E_{off}$			0.85	1.5 mJ
$t_{d(on)}$	<b>Inductive load, <math>T_J = 125^\circ\text{C}</math></b>		38	ns
$t_{ri}$	$I_C = I_{C25}, V_{GE} = 15\text{ V}, R_G = 10\ \Omega$	59	ns	
$E_{on}$	$V_{CE} = 0.5 V_{CES}$ , Note 3	1.5	mJ	
		2.5	mJ	
$t_{d(off)}$		175	ns	
$t_{fi}$		155	ns	
$E_{off}$		2.0	mJ	
$R_{thJC}$			0.65	KW
$R_{thCK}$	(TO-247)	0.25		KW

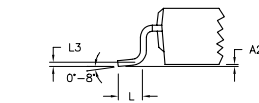
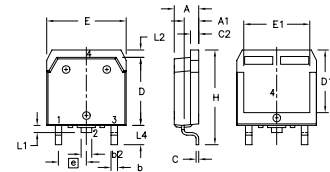
**Reverse Diode (FRED)**
**Characteristic Values**

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ unless otherwise specified)	min.	typ.	max.	
					$V_F$
	$T_J = 125^\circ\text{C}$	2.5		V	
$t_{rr}$	$I_F = 20\text{ A}, V_{GE} = 0\text{ V}, -di_F/dt = 450\text{ A}/\mu\text{s}$	230		ns	
	$V_R = 1200\text{ V}$	400		ns	
$I_{RM}$		23		A	
	$T_J = 125^\circ\text{C}$	27		A	
$R_{thJC}$				0.9	KW

- Notes: 1. Device must be heatsunk for high temperature leakage current measurements to avoid thermal runaway.  
 2. Pulse test,  $t \leq 300\ \mu\text{s}$ , duty cycle  $\leq 2\%$   
 3. Switching times may increase for  $V_{CE}(\text{Clamp}) > 0.8 \cdot V_{CES}$ , higher  $T_J$  or increased  $R_G$ .

**TO-247 AD Outline**


Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.7	5.3	.185	.209
A <sub>1</sub>	2.2	2.54	.087	.102
A <sub>2</sub>	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b <sub>1</sub>	1.65	2.13	.065	.084
b <sub>2</sub>	2.87	3.12	.113	.123
C	.4	.8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L1		4.50		.177
∅P	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15	BSC	242	BSC

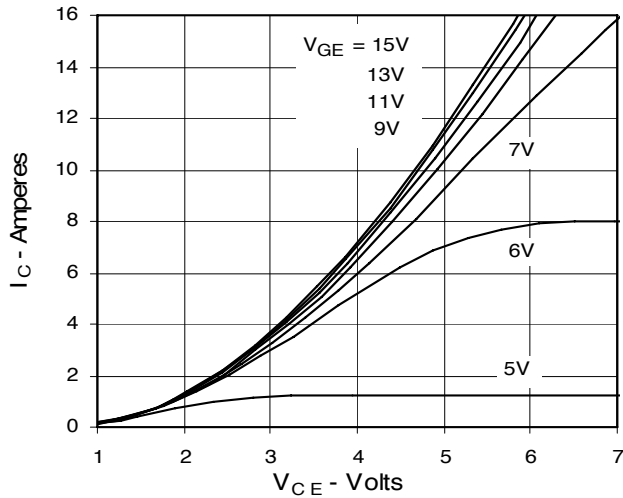
**TO-268 Outline**


Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.9	5.1	.193	.201
A <sub>1</sub>	2.7	2.9	.106	.114
A <sub>2</sub>	.02	.25	.001	.010
b	1.15	1.45	.045	.057
b <sub>2</sub>	1.9	2.1	.75	.83
C	.4	.65	.016	.026
D	13.80	14.00	.543	.551
E	15.85	16.05	.624	.632
E <sub>1</sub>	13.3	13.6	.524	.535
e	5.45	BSC	.215	BSC
H	18.70	19.10	.736	.752
L	2.40	2.70	.094	.106
L1	1.20	1.40	.047	.055
L2	1.00	1.15	.039	.045
L3		0.25	BSC	.010
L4	3.80	4.10	.150	.161

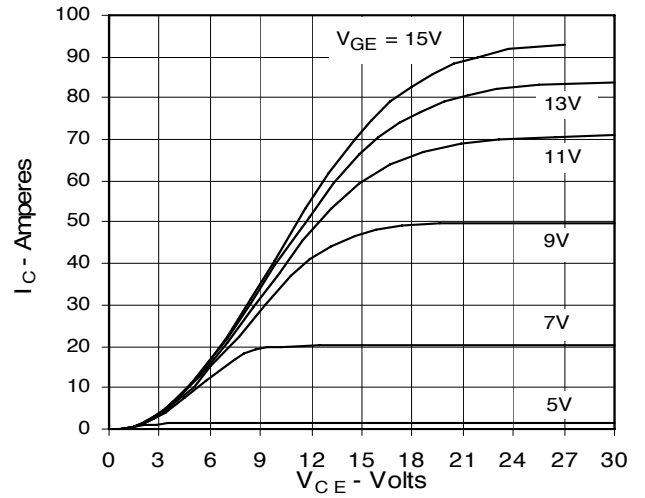
IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:	4,835,592	4,931,844	5,049,961	5,237,481	6,162,665	6,404,065 B1	6,683,344	6,727,585
	4,850,072	5,017,508	5,063,307	5,381,025	6,259,123 B1	6,534,343	6,710,405 B2	6,759,692
	4,881,106	5,034,796	5,187,117	5,486,715	6,306,728 B1	6,583,505	6,710,463	6,771,478 B2

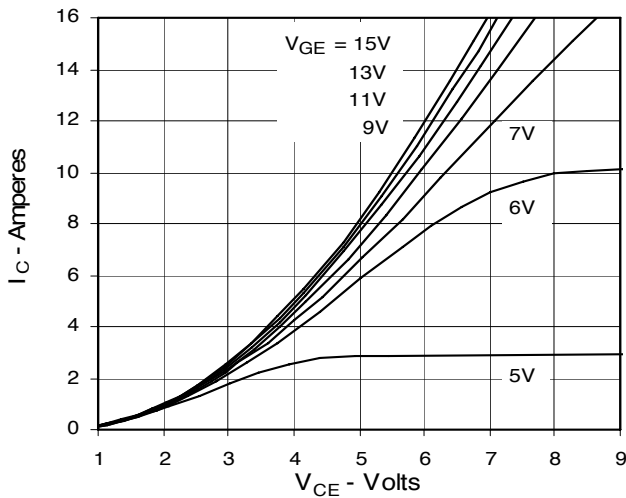
**Fig. 1. Output Characteristics**  
**@ 25 °C**



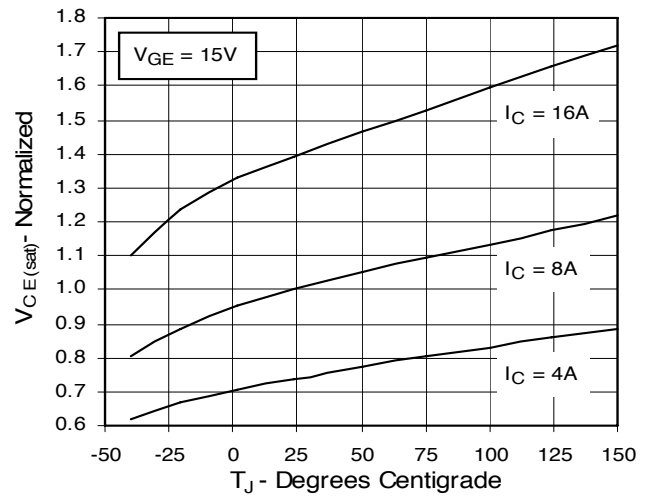
**Fig. 2. Extended Output Characteristics**  
**@ 25 °C**



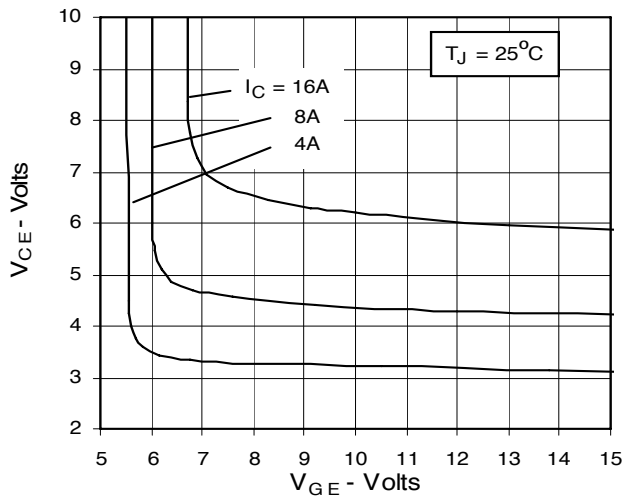
**Fig. 3. Output Characteristics**  
**@ 125 °C**



**Fig. 4. Dependence of  $V_{CE(sat)}$  on Temperature**



**Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter voltage**



**Fig. 6. Input Admittance**

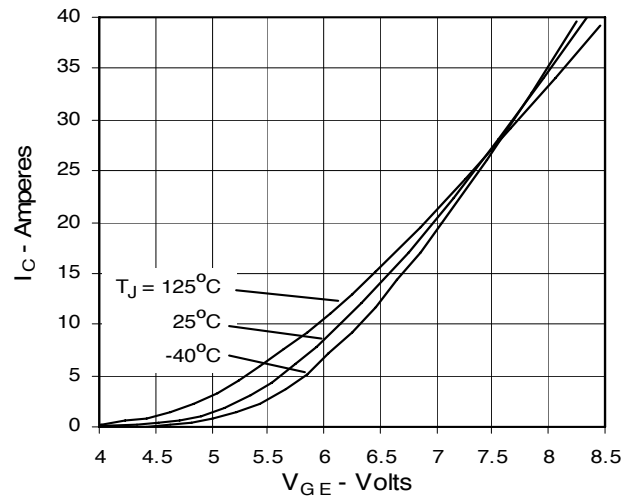


Fig. 7. Transconductance

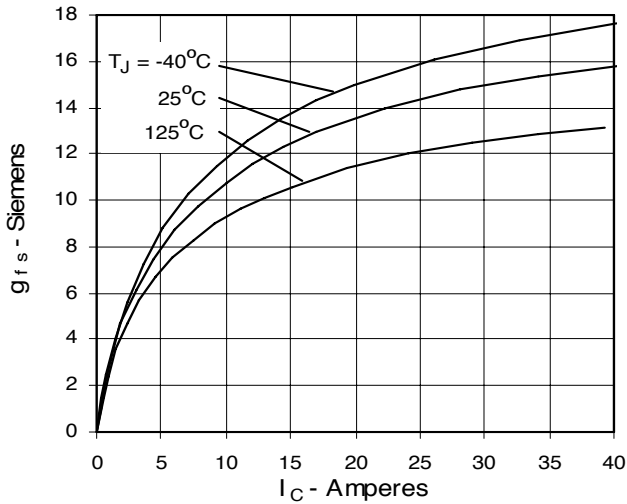


Fig. 8. Dependence of Turn-off Energy Loss on  $R_G$

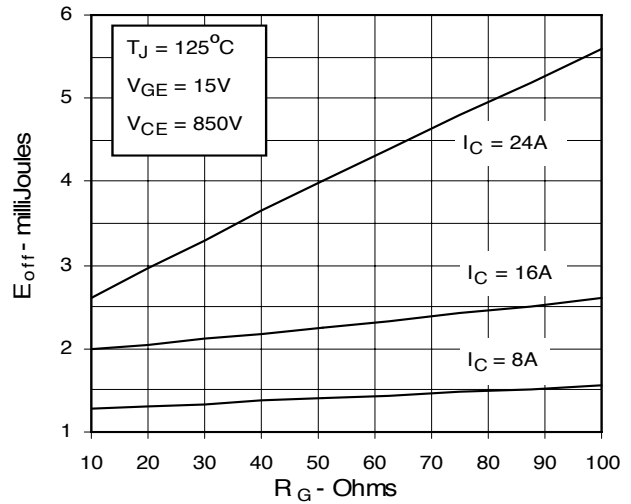


Fig. 9. Dependence of Turn-Off Energy Loss on  $I_C$

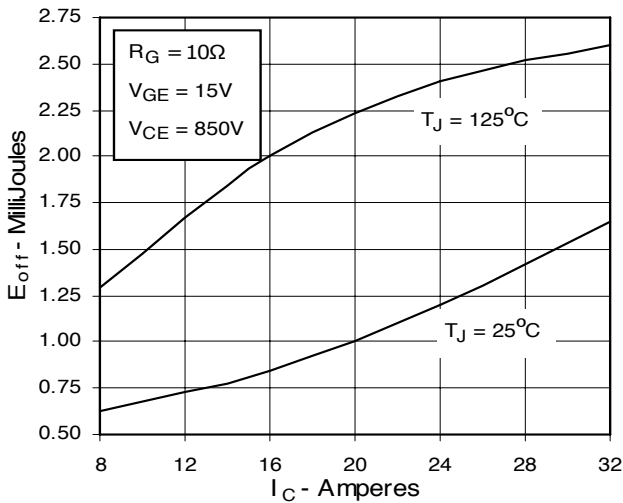


Fig. 10. Dependence of Turn-off Energy Loss on Temperature

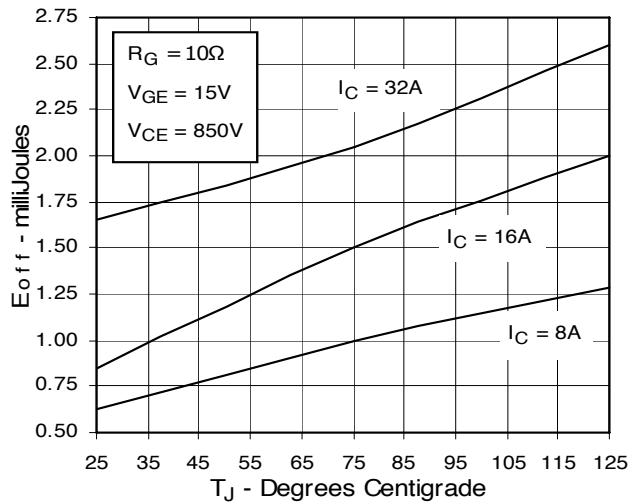


Fig. 11. Dependence of Turn-off Switching Time on  $R_G$

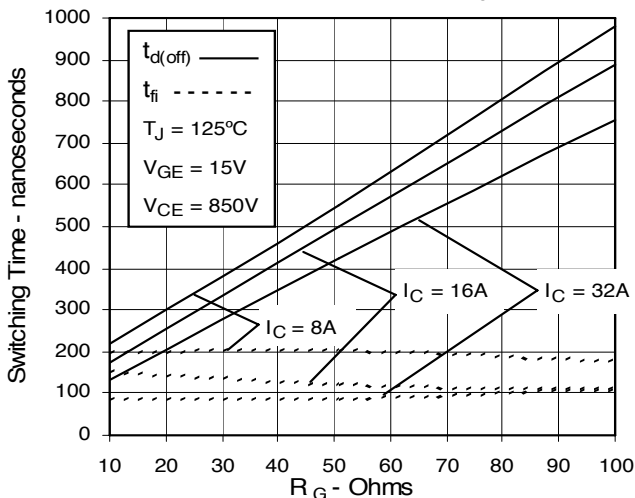
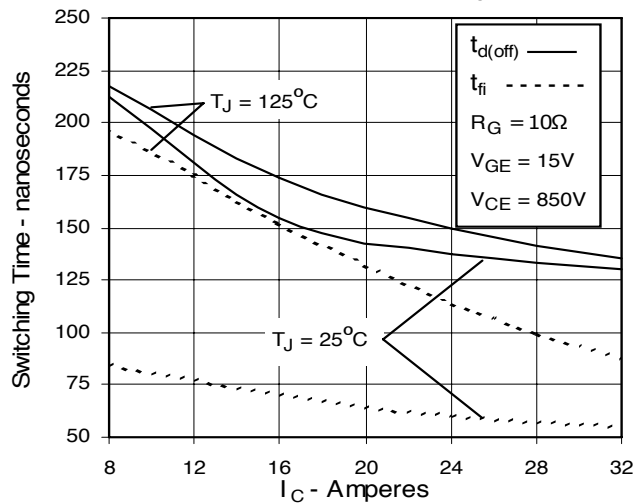
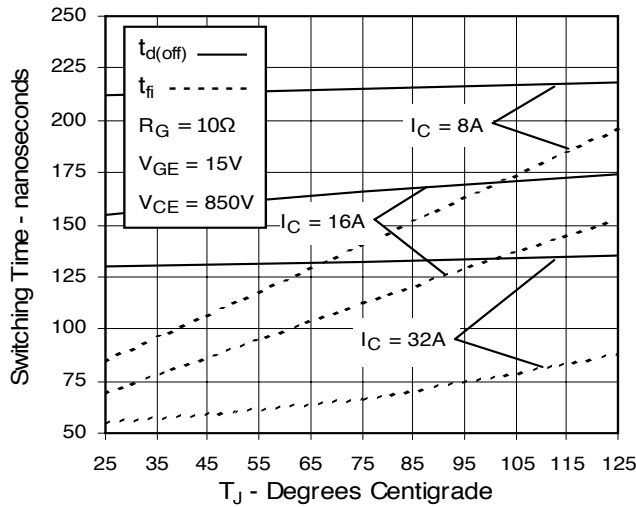


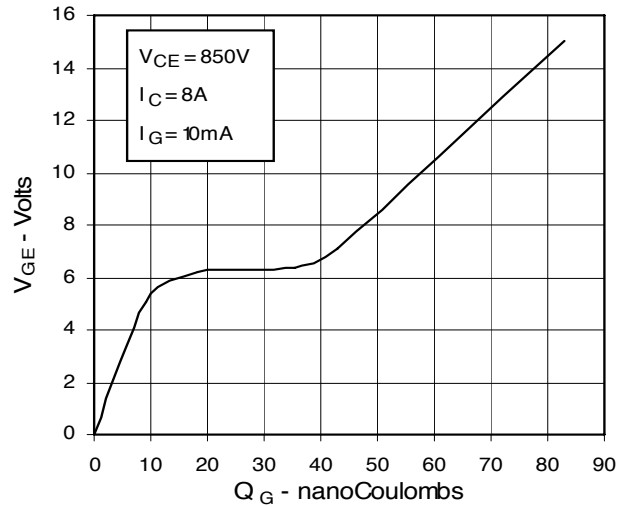
Fig. 12. Dependence of Turn-off Switching Time on  $I_C$



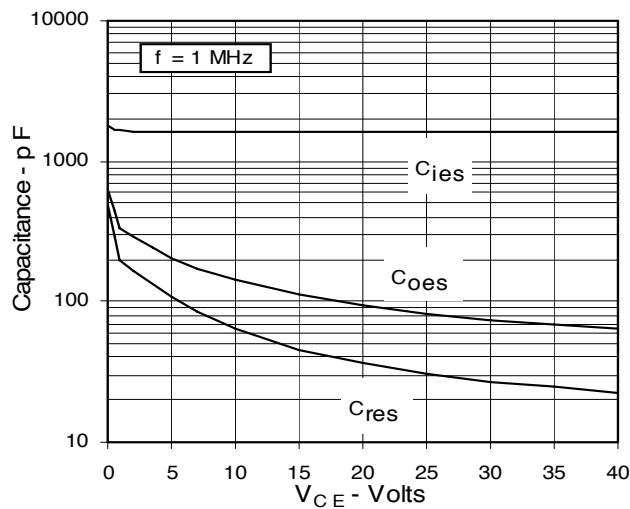
**Fig. 13. Dependence of Turn-off Switching Time on Temperature**



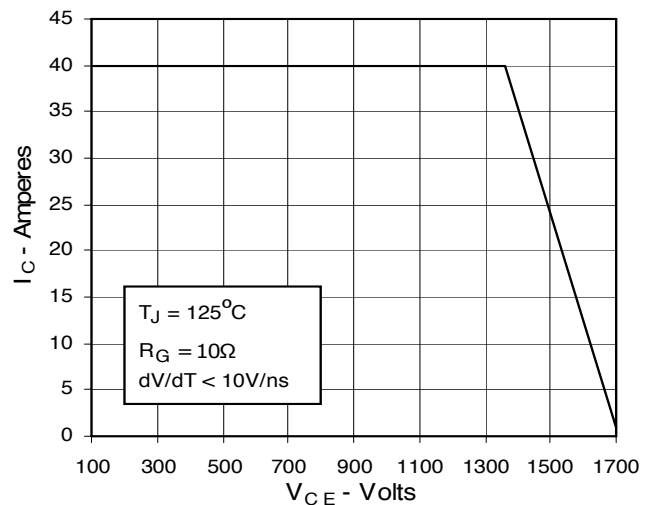
**Fig. 14. Gate Charge**



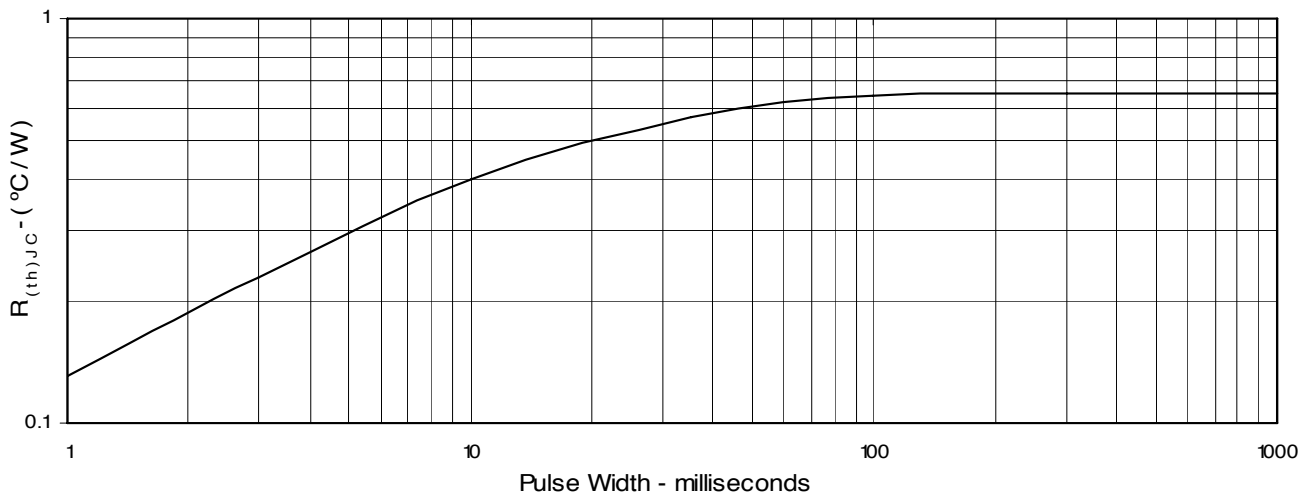
**Fig. 15. Capacitance**



**Fig. 16. Reverse-Bias Safe Operating Area**



**Fig. 17. Maximum Transient Thermal Resistance**



**PRELIMINARY TECHNICAL INFORMATION**

The product presented herein is under development. The Technical Specifications offered are derived from data gathered during objective characterizations of preliminary engineering lots; but also may yet contain some information supplied during a subjective pre-production design evaluation. IXYS reserves the right to change limits, test conditions, and dimensions without notice.